Se	arcn	n notes		

Application No.	Applicant(s)
10/014,742	HEEB, BEAT
Examiner	Art Unit
Hoang-Vu A Nguyen-Ba	2122

SEARCHED				
Class	Subclass	Date	Examiner	
717	140,146	9/1/2004	HAN	
717	148,136	9/1/2004	HAN	
7.17	139	9/1/2004	HAN	
717	118,126	9/1/2004	HAN	
717	114,116	9/1/2004	HAN	
717	151-153	9/1/2004	HAN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Search: USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM-TDB	9/1/2004	HAN		
Non Patent Literature Search: Google	9/1/2004	HAN		
Inventor Search	8/27/2004	HAN		
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